NXP USA Inc. - KMPC8560CPX667JB Datasheet

Understanding Embedded - Microprocessors

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of Embedded - Microprocessors

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details	
Product Status	Obsolete
Core Processor	PowerPC e500
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	667MHz
Co-Processors/DSP	Communications; CPM
RAM Controllers	DDR, SDRAM
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (2)
SATA	-
USB	-
Voltage - I/O	2.5V, 3.3V
Operating Temperature	-40°C ~ 105°C (TA)
Security Features	-
Package / Case	783-BFBGA, FCBGA
Supplier Device Package	783-FCPBGA (29x29)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/kmpc8560cpx667jb

Table 1. Absolute Maximum Ratings [1] (continued)

Characteristic		Symbol	Max Value	Unit	Notes
DDR DRAM I/O voltage		GV_{DD}	–0.3 to 3.63	V	—
Three-speed Ethernet I/O voltage		LV_{DD}	–0.3 to 3.63 –0.3 to 2.75	V	—
CPM, PCI/PCI-X, local bus, RapidIO, 10/100 Ethernet,MII management, DUART, system control and power management, I^2C, and JTAG I/O voltage		OV_{DD}	–0.3 to 3.63	V	3
Input voltage	DDR DRAM signals	MV_{IN}	–0.3 to (GV_{DD} + 0.3)	V	2, 5
	DDR DRAM reference	MV_{REF}	–0.3 to (GV_{DD} + 0.3)	V	2, 5
	Three-speed Ethernet signals	LV_{IN}	–0.3 to (LV_{DD} + 0.3)	V	4, 5
	CPM, Local bus, RapidIO, 10/100 Ethernet, SYSCLK, system control and power management, I^2C, and JTAG signals	OV_{IN}	–0.3 to (OV_{DD} + 0.3)	V	5
	PCI/PCI-X	OV_{IN}	–0.3 to (OV_{DD} + 0.3)	V	6
Storage temperature range		T_{STG}	–55 to 150	°C	—

Notes:

1. Functional and tested operating conditions are given in Table 2. Absolute maximum ratings are stress ratings only, and functional operation at the maximums is not guaranteed. Stresses beyond those listed may affect device reliability or cause permanent damage to the device.
2. **Caution:** MV_{IN} must not exceed GV_{DD} by more than 0.3 V. This limit may be exceeded for a maximum of 20 ms during power-on reset and power-down sequences.
3. **Caution:** OV_{IN} must not exceed OV_{DD} by more than 0.3 V. This limit may be exceeded for a maximum of 20 ms during power-on reset and power-down sequences.
4. **Caution:** LV_{IN} must not exceed LV_{DD} by more than 0.3 V. This limit may be exceeded for a maximum of 20 ms during power-on reset and power-down sequences.
5. $(M,L,O)V_{IN}$ and MV_{REF} may overshoot/undershoot to a voltage and for a maximum duration as shown in Figure 2.
6. OV_{IN} on the PCI interface may overshoot/undershoot according to the PCI Electrical Specification for 3.3-V operation, as shown in Figure 3.

2.1.2 Power Sequencing

The MPC8560 requires its power rails to be applied in a specific sequence in order to ensure proper device operation. These requirements are as follows for power up:

1. V_{DD}, AV_{DD}
2. GV_{DD}, LV_{DD}, OV_{DD} (I/O supplies)

Items on the same line have no ordering requirement with respect to one another. Items on separate lines must be ordered sequentially such that voltage rails on a previous step must reach 90 percent of their value before the voltage rails on the current step reach 10 percent of theirs.

7.2.3 TBI AC Timing Specifications

This section describes the TBI transmit and receive AC timing specifications.

7.2.3.1 TBI Transmit AC Timing Specifications

Table 25 provides the TBI transmit AC timing specifications.

Table 25. TBI Transmit AC Timing Specifications

At recommended operating conditions with LV_{DD} of 3.3 V ± 5%, or LV_{DD}=2.5V ± 5%.

Parameter/Condition	Symbol [1]	Min	Typ	Max	Unit
GTX_CLK clock period	t_{TTX}	—	8.0	—	ns
GTX_CLK duty cycle	t_{TTXH}/t_{TTX}	40	—	60	%
TCG[9:0] setup time GTX_CLK going high	t_{TTKHDV}	2.0	—	—	ns
TCG[9:0] hold time from GTX_CLK going high	t_{TTKHDX}	1.0	—	—	ns
GTX_CLK clock rise and fall time	t_{TTXR}, t_{TTXF} [2,3]	—	—	1.0	ns

Notes:

1. The symbols used for timing specifications herein follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{TTKHDV} symbolizes the TBI transmit timing (TT) with respect to the time from t_{TTX} (K) going high (H) until the referenced data signals (D) reach the valid state (V) or setup time. Also, t_{TTKHDX} symbolizes the TBI transmit timing (TT) with respect to the time from t_{TTX} (K) going high (H) until the referenced data signals (D) reach the invalid state (X) or hold time. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{TTX} represents the TBI (T) transmit (TX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
2. Signal timings are measured at 0.7 V and 1.9 V voltage levels.
3. Guaranteed by design.

Figure 12 shows the TBI transmit AC timing diagram.

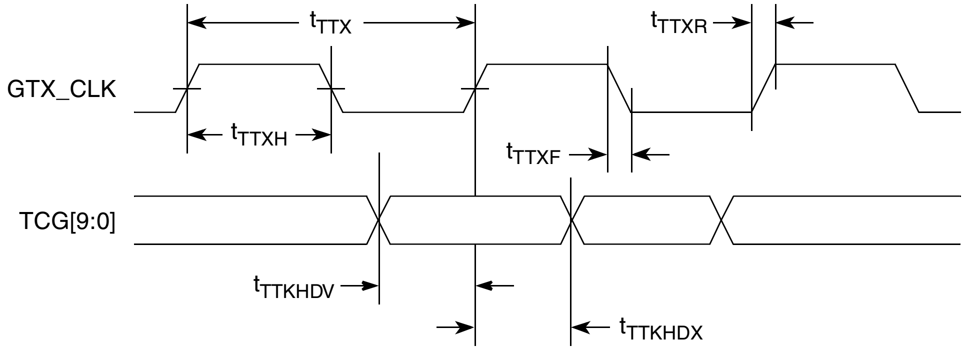


Figure 12. TBI Transmit AC Timing Diagram

Table 28. MII Management DC Electrical Characteristics (continued)

Parameter	Symbol	Min	Max	Unit
Input high current (OV_{DD} = Max, V_{IN} [1] = 2.1 V)	I_{IH}	—	40	μA
Input low current (OV_{DD} = Max, V_{IN} = 0.5 V)	I_{IL}	–600	—	μA

Note:

1.Note that the symbol V_{IN}, in this case, represents the OV_{IN} symbol referenced in Table 1 and Table 2.

7.3.2 MII Management AC Electrical Specifications

Table 29 provides the MII management AC timing specifications.

Table 29. MII Management AC Timing Specifications

At recommended operating conditions with OV_{DD} is 3.3 V ± 5%.

Parameter/Condition	Symbol [1]	Min	Typ	Max	Unit	Notes
MDC frequency	f_{MDC}	0.893	—	10.4	MHz	2, 4
MDC period	t_{MDC}	96	—	1120	ns	
MDC clock pulse width high	t_{MDCH}	32	—	—	ns	
MDC to MDIO valid	t_{MDKHDV}			$2*[1/(f_{ccb\_clk}/8)]$	ns	3
MDC to MDIO delay	t_{MDKHDX}	10	—	$2*[1/(f_{ccb\_clk}/8)]$	ns	3
MDIO to MDC setup time	t_{MDDVKH}	5	—	—	ns	
MDIO to MDC hold time	t_{MDDXKH}	0	—	—	ns	
MDC rise time	t_{MDCR}	—	—	10	ns	4
MDC fall time	t_{MDHF}	—	—	10	ns	4

Notes:

1.The symbols used for timing specifications herein follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{MDKHDX} symbolizes management data timing (MD) for the time t_{MDC} from clock reference (K) high (H) until data outputs (D) are invalid (X) or data hold time. Also, t_{MDDVKH} symbolizes management data timing (MD) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{MDC} clock reference (K) going to the high (H) state or setup time. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).

2.This parameter is dependent on the CCB clock speed (that is, for a CCB clock of 267 MHz, the maximum frequency is 8.3 MHz and the minimum frequency is 1.2 MHz; for a CCB clock of 333 MHz, the maximum frequency is 10.4 MHz and the minimum frequency is 1.5 MHz).

3.This parameter is dependent on the CCB clock speed (that is, for a CCB clock of 267 MHz, the delay is 60 ns and for a CCB clock of 333 MHz, the delay is 48 ns).

4.Guaranteed by design.

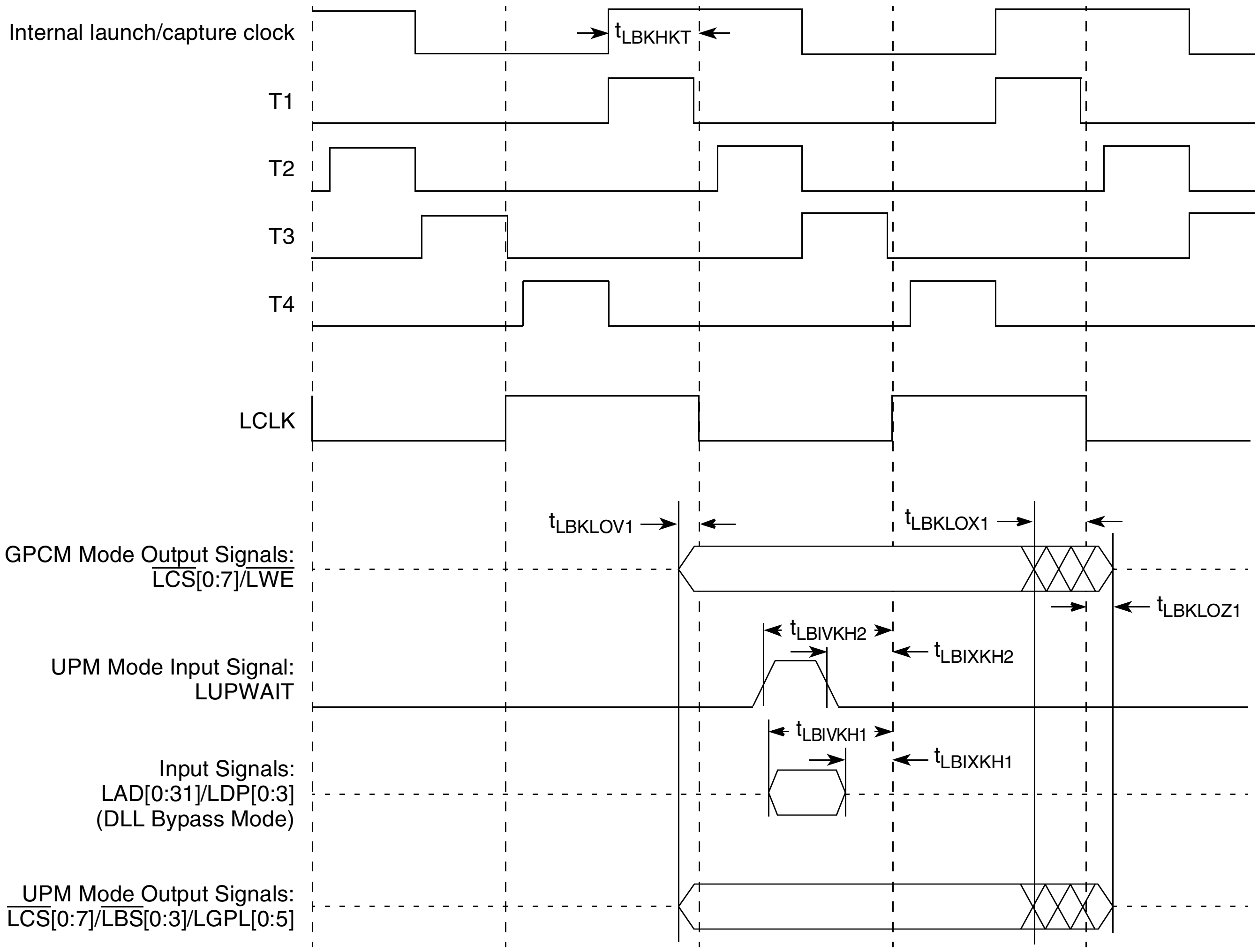


Figure 22. Local Bus Signals, GPCM/UPM Signals for LCCR[CLKDIV] = 4 or 8 (DLL Bypass Mode)

9 CPM

This section describes the DC and AC electrical specifications for the CPM of the MPC8560.

9.1 CPM DC Electrical Characteristics

Table 33 provides the DC electrical characteristics for the MPC8560 CPM.

Table 33. CPM DC Electrical Characteristics

Characteristic	Symbol	Min	Max	Unit	Notes
Input high voltage	V_{IH}	2.0	3.465	V	1
Input low voltage	V_{IL}	GND	0.8	V	1, 2
Output high voltage (I_{OH} = –8.0 mA)	V_{OH}	2.4	—	V	1
Output low voltage (I_{OL} = 8.0 mA)	V_{OL}	—	0.5	V	1

Table 33. CPM DC Electrical Characteristics (continued)

Characteristic	Symbol	Min	Max	Unit	Notes
Output high voltage ($I_{OH} = –2.0$ mA)	V_{OH}	2.4	—	V	1
Output low voltage (I_{OL} = 3.2 mA)	V_{OL}	—	0.4	V	1

Note:

1. This specification applies to the following pins: PA[0–31], PB[4–31], PC[0–31], and PD[4–31].
2. V_{IL}(max) for the IIC interface is 0.8 V rather than the 1.5 V specified in the IIC standard

9.2 CPM AC Timing Specifications

Table 34 and Table 35 provide the CPM input and output AC timing specifications, respectively.

NOTE: Rise/Fall Time on CPM Input Pins

It is recommended that the rise/fall time on CPM input pins should not exceed 5 ns. This should be enforced especially on clock signals. Rise time refers to signal transitions from 10% to 90% of VCC; fall time refers to transitions from 90% to 10% of VCC.

Table 34. CPM Input AC Timing Specifications [1]

Characteristic	Symbol [2]	Min [3]	Unit
FCC inputs—internal clock (NMSI) input setup time	t_{FIIVKH}	6	ns
FCC inputs—internal clock (NMSI) hold time	t_{FIIXKH}	0	ns
FCC inputs—external clock (NMSI) input setup time	t_{FEIVKH}	2.5	ns
FCC inputs—external clock (NMSI) hold time	t_{FEIXKH}b	2	ns
SCC/SPI inputs—internal clock (NMSI) input setup time	t_{NIIVKH}	6	ns
SCC/SPI inputs—internal clock (NMSI) input hold time	t_{NIIXKH}	0	ns
SCC/SPI inputs—external clock (NMSI) input setup time	t_{NEIVKH}	4	ns
SCC/SPI inputs—external clock (NMSI) input hold time	t_{NEIXKH}	2	ns
TDM inputs/SI—input setup time	t_{TDIVKH}	4	ns
TDM inputs/SI—hold time	t_{TDIXKH}	3	ns

Figure 24 shows the FCC internal clock.

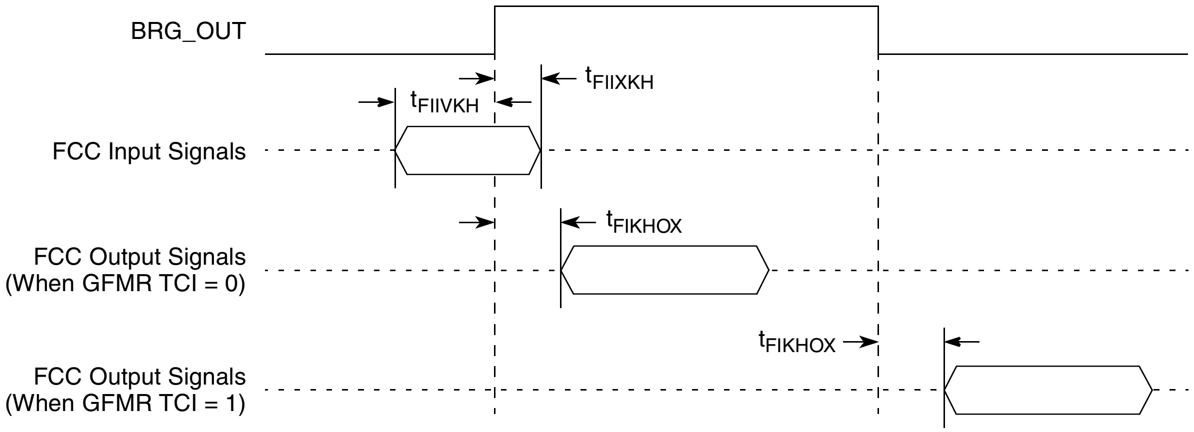


Figure 24. FCC Internal AC Timing Clock Diagram

Figure 25 shows the FCC external clock.

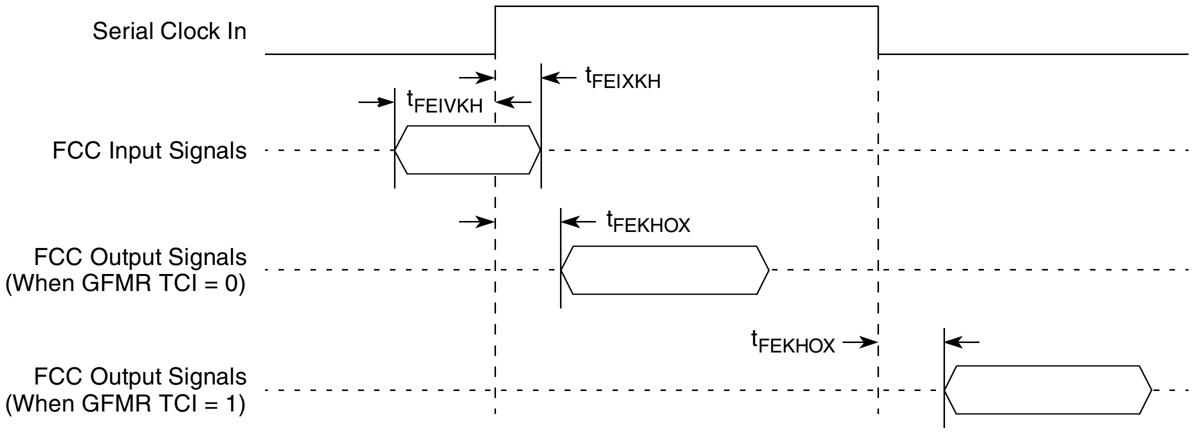


Figure 25. FCC External AC Timing Clock Diagram

Figure 26 shows Ethernet collision timing on FCCs.

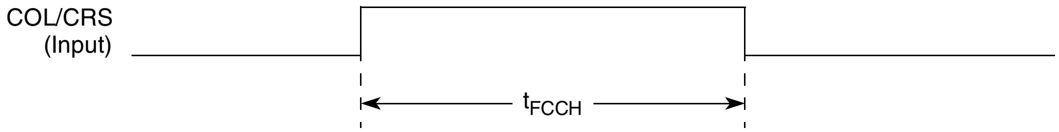


Figure 26. Ethernet Collision AC Timing Diagram (FCC)

Table 36 shows CPM I^2C AC Timing.

Table 36. CPM I^2C AC Timing

Characteristic	Symbol	Min	Max	Unit
SCL clock frequency (slave)	f_{SCL}	0	F_{MAX}[1]	Hz
SCL clock frequency (master)	f_{SCL}	BRGCLK/16512	BRGCLK/48	Hz
Bus free time between transmissions	t_{SDHDL}	$1/(2.2 * f_{SCL})$	—	s
Low period of SCL	t_{SCLCH}	$1/(2.2 * f_{SCL})$	—	s
High period of SCL	t_{SCHCL}	$1/(2.2 * f_{SCL})$	—	s
Start condition setup time [2]	t_{SCHDL}	$2/(\text{divider} * f_{SCL})$	—	s
Start condition hold time [2]	t_{SDLCL}	$3/(\text{divider} * f_{SCL})$	—	s
Data hold time [2]	t_{SCLDX}	$2/(\text{divider} * f_{SCL})$	—	s
Data setup time [2]	t_{SDVCH}	$3/(\text{divider} * f_{SCL})$	—	s
SDA/SCL rise time	t_{SRISE}	—	$1/(10 * f_{SCL})$	s
SDA/SCL fall time	t_{SFALL}	—	$1/(33 * f_{SCL})$	s
Stop condition setup time	t_{SCHDH}	$2/(\text{divider} * f_{SCL})$	—	s

Notes:

1. F_{MAX} = BRGCLK/(min_divider*prescaler). Where prescaler=25-I2MODE[PDIV]; and min_divider=12 if digital filter disabled and 18 if enabled.

   Example #1: if I2MODE[PDIV]=11 (prescaler=4) and I2MODE[FLT]=0 (digital filter disabled) then FMAX=BRGCLK/48

   Example #2: if I2MODE[PDIV]=00 (prescaler=32) and I2MODE[FLT]=1 (digital filter enabled) then FMAX=BRGCLK/576

2. divider = f_{SCL}/prescaler.

   In master mode: divider = BRGCLK/(f_{SCL}*prescaler) = 2*(I2BRG[DIV]+3)

   In slave mode: divider = BRGCLK/(f_{SCL}*prescaler)

Figure 30 is a a diagram of CPM I^2C Bus Timing.

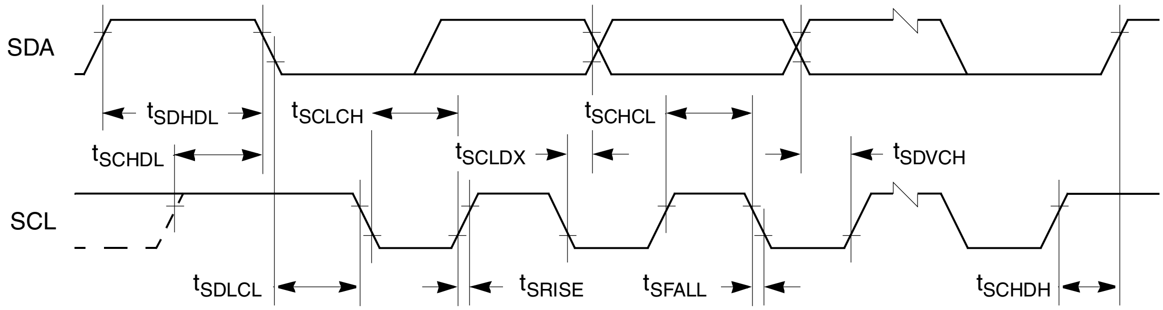


Figure 30. CPM I^2C Bus Timing Diagram

Figure 35 provides the test access port timing diagram.

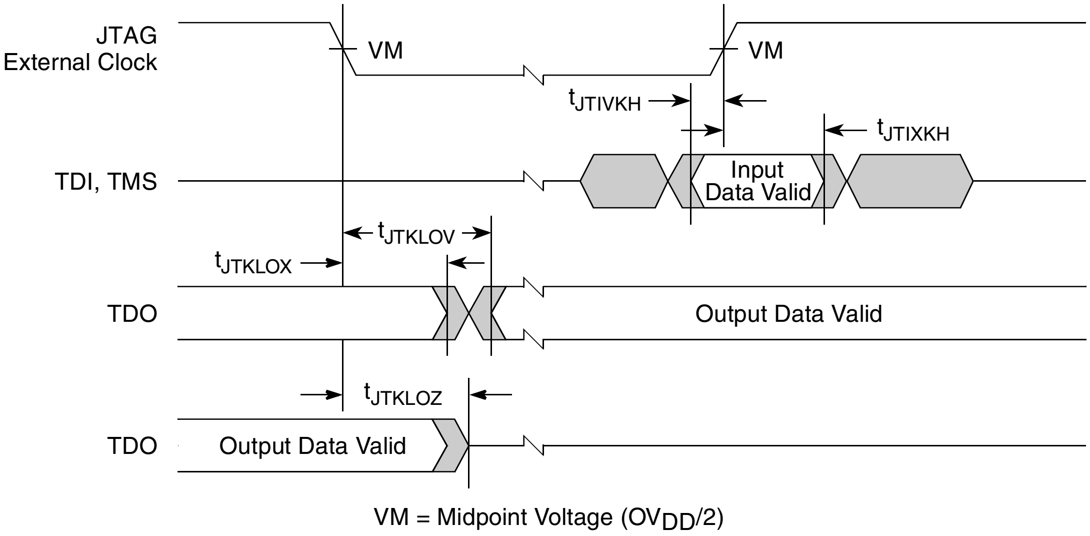


Figure 35. Test Access Port Timing Diagram

11 I^{2}C

This section describes the DC and AC electrical characteristics for the I^{2}C interface of the MPC8560.

11.1 I^{2}C DC Electrical Characteristics

Table 40 provides the DC electrical characteristics for the I^{2}C interface of the MPC8560.

Table 40. I^{2}C DC Electrical Characteristics

At recommended operating conditions with OV_{DD} of 3.3 V ± 5%.

Parameter	Symbol	Min	Max	Unit	Notes
Input high voltage level	V_{IH}	$0.7 \times OV_{DD}$	OV_{DD}+ 0.3	V	—
Input low voltage level	V_{IL}	–0.3	$0.3 \times OV_{DD}$	V	—
Low level output voltage	V_{OL}	0	$0.2 \times OV_{DD}$	V	1
Pulse width of spikes which must be suppressed by the input filter	t_{I2KHKL}	0	50	ns	2
Input current each I/O pin (input voltage is between $0.1 \times OV_{DD}$ and $0.9 \times OV_{DD}$(max)	I_I	–10	10	µA	3
Capacitance for each I/O pin	C_I	—	10	pF	—

Notes:

1. Output voltage (open drain or open collector) condition = 3 mA sink current.
2. Refer to the *MPC8560 PowerQUICC III Integrated Communications Processor Preliminary Reference Manual* for information on the digital filter used.
3. I/O pins will obstruct the SDA and SCL lines if OV_{DD} is switched off.

11.2 I²C AC Electrical Specifications

Table 41 provides the AC timing parameters for the I²C interface of the MPC8560.

Table 41. I²C AC Electrical Specifications

All values refer to V_{IH} (min) and V_{IL} (max) levels (see Table 40).

Parameter	Symbol [1]	Min	Max	Unit
SCL clock frequency	f_{I2C}	0	400	kHz
Low period of the SCL clock	t_{I2CL} [6]	1.3	—	μs
High period of the SCL clock	t_{I2CH} [6]	0.6	—	μs
Setup time for a repeated START condition	t_{I2SVKH} [6]	0.6	—	μs
Hold time (repeated) START condition (after this period, the first clock pulse is generated)	t_{I2SXKL} [6]	0.6	—	μs
Data setup time	t_{I2DVKH} [6]	100	—	ns
Data hold time: CBUS compatible masters I²C bus devices	t_{I2DXKL}	 — 0 [2]	 — 0.9 [3]	μs
Set-up time for STOP condition	t_{I2PVKH}	0.6	—	μs
Bus free time between a STOP and START condition	t_{I2KHDX}	1.3	—	μs
Noise margin at the LOW level for each connected device (including hysteresis)	V_{NL}	$0.1 \times OV_{DD}$	—	V
Noise margin at the HIGH level for each connected device (including hysteresis)	V_{NH}	$0.2 \times OV_{DD}$	—	V

Notes:

1. The symbols used for timing specifications herein follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{I2DVKH} symbolizes I²C timing (I2) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{I2C} clock reference (K) going to the high (H) state or setup time. Also, t_{I2SXKL} symbolizes I²C timing (I2) for the time that the data with respect to the start condition (S) went invalid (X) relative to the t_{I2C} clock reference (K) going to the low (L) state or hold time. Also, t_{I2PVKH} symbolizes I²C timing (I2) for the time that the data with respect to the stop condition (P) reaching the valid state (V) relative to the t_{I2C} clock reference (K) going to the high (H) state or setup time. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
2. MPC8560 provides a hold time of at least 300 ns for the SDA signal (referred to the V_{IHmin} of the SCL signal) to bridge the undefined region of the falling edge of SCL.
3. The maximum t_{I2DVKH} has only to be met if the device does not stretch the LOW period (t_{I2CL}) of the SCL signal.
4. C_B = capacitance of one bus line in pF.
6. Guaranteed by design.

Figure 16 provides the AC test load for the I²C.

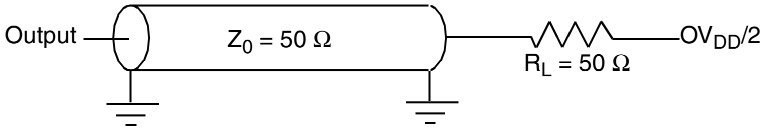


Figure 36. I²C AC Test Load

13.3.2 RapidIO Receiver AC Timing Specifications

The RapidIO receiver AC timing specifications are provided in Table 51. A receiver shall comply with the specifications for each data rate/frequency for which operation of the receiver is specified. Unless otherwise specified, these specifications are subject to the following conditions.

- The specifications apply over the supply voltage and ambient temperature ranges specified by the device vendor.
- The specifications apply for any combination of data patterns on the data signals.
- The specifications apply over the receiver common mode and differential input voltage ranges.
- Clock specifications apply only to clock signals.
- Data specifications apply only to data signals (FRAME, D[0:7])

Table 51. RapidIO Receiver AC Timing Specifications—500 Mbps Data Rate

Characteristic	Symbol	Range		Unit	Notes
		Min	Max		
Duty cycle of the clock input	DC	47	53	%	1, 5
Data valid	DV	1080		ps	2
Allowable static skew between any two data inputs within a 8-/9-bit group	t_{DPAIR}	—	380	ps	3
Allowable static skew of data inputs to associated clock	$t_{SKEW,PAIR}$	–300	300	ps	4

Notes:

1.Measured at $V_{ID} = 0$ V.

2.Measured using the RapidIO receive mask shown in Figure 46.

3.See Figure 49.

4.See Figure 48 and Figure 49.

5.Guaranteed by design.

Table 52. RapidIO Receiver AC Timing Specifications—750 Mbps Data Rate

Characteristic	Symbol	Range		Unit	Notes
		Min	Max		
Duty cycle of the clock input	DC	47	53	%	1, 5
Data valid	DV	600	—	ps	2
Allowable static skew between any two data inputs within a 8-/9-bit group	t_{DPAIR}	—	400	ps	3
Allowable static skew of data inputs to associated clock	$t_{SKEW,PAIR}$	–267	267	ps	4

Notes:

1.Measured at $V_{ID} = 0$ V.

2.Measured using the RapidIO receive mask shown in Figure 46.

3.See Figure 49.

4.See Figure 48 and Figure 49.

5.Guaranteed by design.

enough that increasing the length of the sequence does not cause the resulting eye pattern to change from one that complies with the RapidIO receive mask to one that does not comply with the mask. The data carried by any given data signal in the interface may not be correlated with the data carried by any other data signal in the interface. The zero-crossings of the clock associated with a data signal shall be used as the timing reference for aligning the multiple recordings of the data signal when the recordings are overlaid.

While the method used to make the recordings and overlay them to form the eye pattern is not specified, the method used shall be demonstrably equivalent to the following method. The signal under test is repeatedly recorded with a digital oscilloscope in infinite persistence mode. Each recording is triggered by a zero-crossing of the clock associated with the data signal under test. Roughly half of the recordings are triggered by positive-going clock zero-crossings and roughly half are triggered by negative-going clock zero-crossings. Each recording is at least 1.9 UI in length (to ensure that at least one complete eye is formed) and begins 0.5 UI before the trigger point (0.5 UI before the associated clock zero-crossing). Depending on the length of the individual recordings used to generate the eye pattern, one or more complete eyes will be formed. Regardless of the number of eyes, the eye whose center is immediately to the right of the trigger point is the eye used for compliance testing.

An example of an eye pattern generated using the above method with recordings 3 UI in length is shown in Figure 47. In this example, there is no skew between the signal under test and the associated clock used to trigger the recordings. If skew was present, the eye pattern would be shifted to the left or right relative to the oscilloscope trigger point.

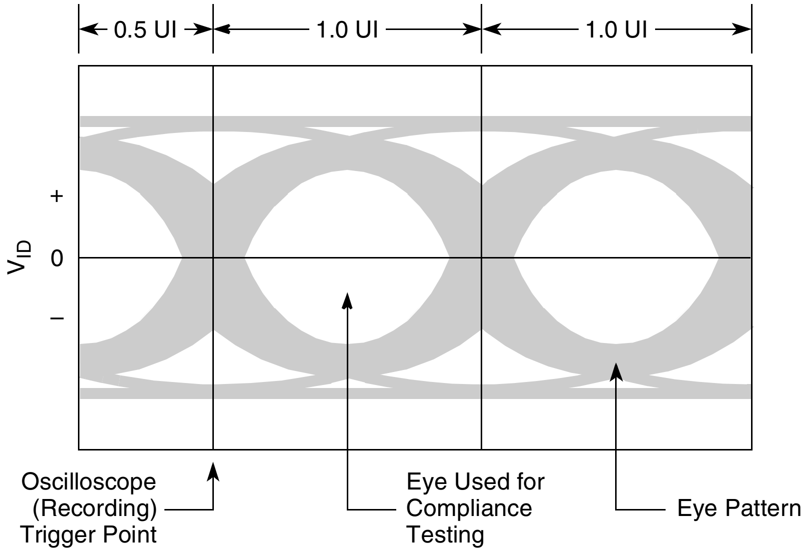


Figure 47. Example Receiver Input Eye Pattern

14 Package and Pin Listings

This section details package parameters, pin assignments, and dimensions.

14.1 Package Parameters for the MPC8560 FC-PBGA

The package parameters are as provided in the following list. The package type is 29 mm × 29 mm, 783 flip chip plastic ball grid array (FC-PBGA).

Die size	12.2 mm × 9.5 mm
Package outline	29 mm × 29 mm
Interconnects	783
Pitch	1 mm
Minimum module height	3.07 mm
Maximum module height	3.75 mm
Solder Balls	62 Sn/36 Pb/2 Ag
Ball diameter (typical)	0.5 mm

3. Maximum solder ball diameter measured parallel to datum A.
4. Datum A, the seating plane, is defined by the spherical crowns of the solder balls.
5. Capacitors may not be present on all devices.
6. Caution must be taken not to short capacitors or exposed metal capacitor pads on package top.
7. The socket lid must always be oriented to A1.

14.3 Pinout Listings

Table 54 provides the pin-out listing for the MPC8560, 783 FC-PBGA package.

Table 54. MPC8560 Pinout Listing

Signal	Package Pin Number	Pin Type	Power Supply	Notes
PCI/PCI-X				
PCI_AD[63:0]	AA14, AB14, AC14, AD14, AE14, AF14, AG14, AH14, V15, W15, Y15, AA15, AB15, AC15, AD15, AG15, AH15, V16, W16, AB16, AC16, AD16, AE16, AF16, V17, W17, Y17, AA17, AB17, AE17, AF17, AF18, AH6, AD7, AE7, AH7, AB8, AC8, AF8, AG8, AD9, AE9, AF9, AG9, AH9, W10, Y10, AA10, AE11, AF11, AG11, AH11, V12, W12, Y12, AB12, AD12, AE12, AG12, AH12, V13, Y13, AB13, AC13	I/O	OV_{DD}	17
PCI_C_$\overline{\text{BE}}$[7:0]	AG13, AH13, V14, W14, AH8, AB10, AD11, AC12	I/O	OV_{DD}	17
PCI_PAR	AA11	I/O	OV_{DD}	—
PCI_PAR64	Y14	I/O	OV_{DD}	—
$\overline{\text{PCI\_FRAME}}$	AC10	I/O	OV_{DD}	2
$\overline{\text{PCI\_TRDY}}$	AG10	I/O	OV_{DD}	2
$\overline{\text{PCI\_IRDY}}$	AD10	I/O	OV_{DD}	2
$\overline{\text{PCI\_STOP}}$	V11	I/O	OV_{DD}	2
$\overline{\text{PCI\_DEVSEL}}$	AH10	I/O	OV_{DD}	2
PCI_IDSEL	AA9	I	OV_{DD}	—
$\overline{\text{PCI\_REQ64}}$	AE13	I/O	OV_{DD}	5, 10
$\overline{\text{PCI\_ACK64}}$	AD13	I/O	OV_{DD}	2
$\overline{\text{PCI\_PERR}}$	W11	I/O	OV_{DD}	2
$\overline{\text{PCI\_SERR}}$	Y11	I/O	OV_{DD}	2, 4
$\overline{\text{PCI\_REQ0}}$	AF5	I/O	OV_{DD}	—
$\overline{\text{PCI\_REQ}}$[1:4]	AF3, AE4, AG4, AE5	I	OV_{DD}	—
$\overline{\text{PCI\_GNT}}$[0]	AE6	I/O	OV_{DD}	—
$\overline{\text{PCI\_GNT}}$[1:4]	AG5, AH5, AF6, AG6	O	OV_{DD}	5, 9

Table 60. Package Thermal Characteristics (continued)

Characteristic	Symbol	Value	Unit	Notes
Junction-to-case thermal	$R_{\theta JC}$	0.8	°C/W	4

Notes

1. Junction temperature is a function of die size, on-chip power dissipation, package thermal resistance, mounting site (board) temperature, ambient temperature, air flow, power dissipation of other components on the board, and board thermal resistance
2. Per JEDEC JESD51-6 with the board horizontal.
3. Thermal resistance between the die and the printed-circuit board per JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.
4. Thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1). Cold plate temperature is used for case temperature; measured value includes the thermal resistance of the interface layer.

16.2 Thermal Management Information

This section provides thermal management information for the flip chip plastic ball grid array (FC-PBGA) package for air-cooled applications. Proper thermal control design is primarily dependent on the system-level design—the heat sink, airflow, and thermal interface material. The recommended attachment method to the heat sink is illustrated in Figure 51. The heat sink should be attached to the printed-circuit board with the spring force centered over the die. This spring force should not exceed 10 pounds force.

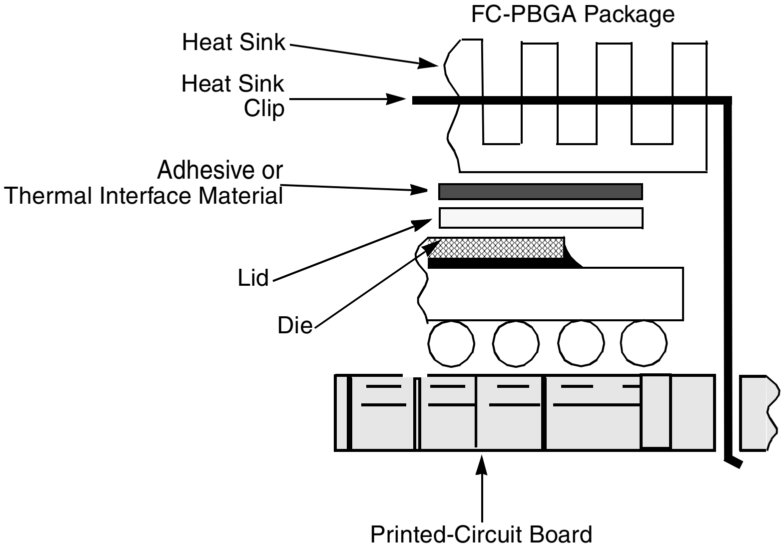


Figure 51. Package Exploded Cross-Sectional View with Several Heat Sink Options

The system board designer can choose between several types of heat sinks to place on the MPC8560. There are several commercially-available heat sinks from the following vendors:

Aavid Thermalloy 603-224-9988
80 Commercial St.
Concord, NH 03301
Internet: www.aavidthermalloy.com

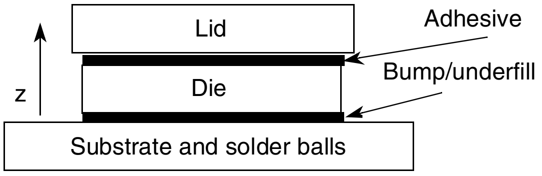
Alpha Novatech 473 Sapena Ct. #15 Santa Clara, CA 95054 Internet: www.alphanovatech.com	408-749-7601
International Electronic Research Corporation (IERC) 413 North Moss St. Burbank, CA 91502 Internet: www.ctscorp.com	818-842-7277
Millennium Electronics (MEI) Loroco Sites 671 East Brokaw Road San Jose, CA 95112 Internet: www.mei-millennium.com	408-436-8770
Tyco Electronics Chip Coolers™ P.O. Box 3668 Harrisburg, PA 17105-3668 Internet: www.chipcoolers.com	800-522-6752
Wakefield Engineering 33 Bridge St. Pelham, NH 03076 Internet: www.wakefield.com	603-635-5102

Ultimately, the final selection of an appropriate heat sink depends on many factors, such as thermal performance at a given air velocity, spatial volume, mass, attachment method, assembly, and cost. Several heat sinks offered by Aavid Thermalloy, Alpha Novatech, IERC, Chip Coolers, Millennium Electronics, and Wakefield Engineering offer different heat sink-to-ambient thermal resistances, that will allow the MPC8560 to function in various environments.

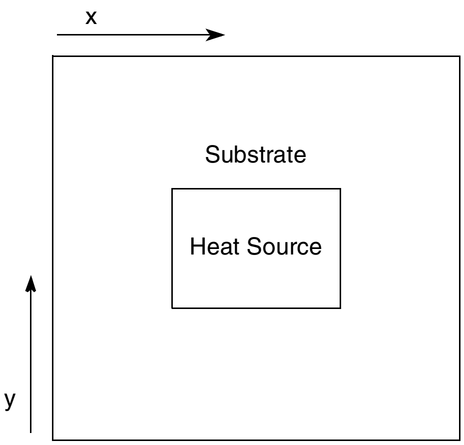
16.2.1 Recommended Thermal Model

For system thermal modeling, the MPC8560 thermal model is shown in Figure 52. Five cuboids are used to represent this device. To simplify the model, the solder balls and substrate are modeled as a single block 29x29x1.47 mm with the conductivity adjusted accordingly. For modeling, the planar dimensions of the die are rounded to the nearest mm, so the die is modeled as 10x12 mm at a thickness of 0.76 mm. The bump/underfill layer is modeled as a collapsed resistance between the die and substrate assuming a conductivity of 0.6 in-plane and 1.9 W/m•K in the thickness dimension of 0.76 mm. The lid attach adhesive is also modeled as a collapsed resistance with dimensions of 10x12x0.050 mm and the conductivity of 1 W/m•K. The nickel plated copper lid is modeled as 12x14x1 mm. Note that the die and lid are not centered on the substrate; there is a 1.5 mm offset documented in the case outline drawing in Figure 50.

Conductivity	Value	Unit
Lid (12 × 14 × 1 mm)		
k_x	360	W/(m × K)
k_y	360	
k_z	360	
Lid Adhesive—Collapsed resistance (10 × 12 × 0.050 mm)		
k_x	1	
k_y	1	
k_z	1	
Die (10 × 12 × 0.76 mm)		
Bump/Underfill—Collapsed resistance (10 × 12 × 0.070 mm)		
k_x	0.6	
k_y	0.6	
k_z	1.9	
Substrate and Solder Balls (29 × 29 × 1.47 mm)		
k_x	10.2	
k_y	10.2	
k_z	1.6	



Side View of Model (Not to Scale)



Top View of Model (Not to Scale)

Figure 52. MPC8560 Thermal Model

16.2.2 Internal Package Conduction Resistance

For the packaging technology, shown in Table 60, the intrinsic internal conduction thermal resistance paths are as follows:

- The die junction-to-case thermal resistance
- The die junction-to-board thermal resistance

Thermagon Inc. 4707 Detroit Ave. Cleveland, OH 44102 Internet: www.thermagon.com	888-246-9050

16.2.4 Heat Sink Selection Examples

The following section provides a heat sink selection example using one of the commercially available heat sinks.

16.2.4.1 Case 1

For preliminary heat sink sizing, the die-junction temperature can be expressed as follows:

$$T_J = T_I + T_R + (\theta_{JC} + \theta_{INT} + \theta_{SA}) \times P_D$$

where

T_J is the die-junction temperature

T_I is the inlet cabinet ambient temperature

T_R is the air temperature rise within the computer cabinet

θ_{JC} is the junction-to-case thermal resistance

θ_{INT} is the adhesive or interface material thermal resistance

θ_{SA} is the heat sink base-to-ambient thermal resistance

P_D is the power dissipated by the device

During operation the die-junction temperatures (T_J) should be maintained within the range specified in Table 2. The temperature of air cooling the component greatly depends on the ambient inlet air temperature and the air temperature rise within the electronic cabinet. An electronic cabinet inlet-air temperature (T_A) may range from 30° to 40°C. The air temperature rise within a cabinet (T_R) may be in the range of 5° to 10°C. The thermal resistance of some thermal interface material (θ_{INT}) may be about 1°C/W. Assuming a T_I of 30°C, a T_R of 5°C, a FC-PBGA package $\theta_{JC} = 0.8$, and a power consumption (P_D) of 7.0 W, the following expression for T_J is obtained:

$$\text{Die-junction temperature: } T_J = 30°\text{C} + 5°\text{C} + (0.8°\text{C/W} + 1.0°\text{C/W} + \theta_{SA}) \times 7.0\text{ W}$$

The heat sink-to-ambient thermal resistance (θ_{SA}) versus airflow velocity for a Thermalloy heat sink #2328B is shown in Figure 55.

Assuming an air velocity of 2 m/s, we have an effective θ_{SA+} of about 3.3°C/W, thus

$$T_J = 30°\text{C} + 5°\text{C} + (0.8°\text{C/W} + 1.0°\text{C/W} + 3.3°\text{C/W}) \times 7.0\text{ W},$$

resulting in a die-junction temperature of approximately 71°C which is well within the maximum operating temperature of the component.

17.8 JTAG Configuration Signals

Boundary-scan testing is enabled through the JTAG interface signals. The $\overline{\text{TRST}}$ signal is optional in the IEEE 1149.1 specification, but is provided on all processors that implement the Power Architecture. The device requires $\overline{\text{TRST}}$ to be asserted during reset conditions to ensure the JTAG boundary logic does not interfere with normal chip operation. While it is possible to force the TAP controller to the reset state using only the TCK and TMS signals, generally systems will assert $\overline{\text{TRST}}$ during the power-on reset flow. Simply tying $\overline{\text{TRST}}$ to $\overline{\text{HRESET}}$ is not practical because the JTAG interface is also used for accessing the common on-chip processor (COP) function.

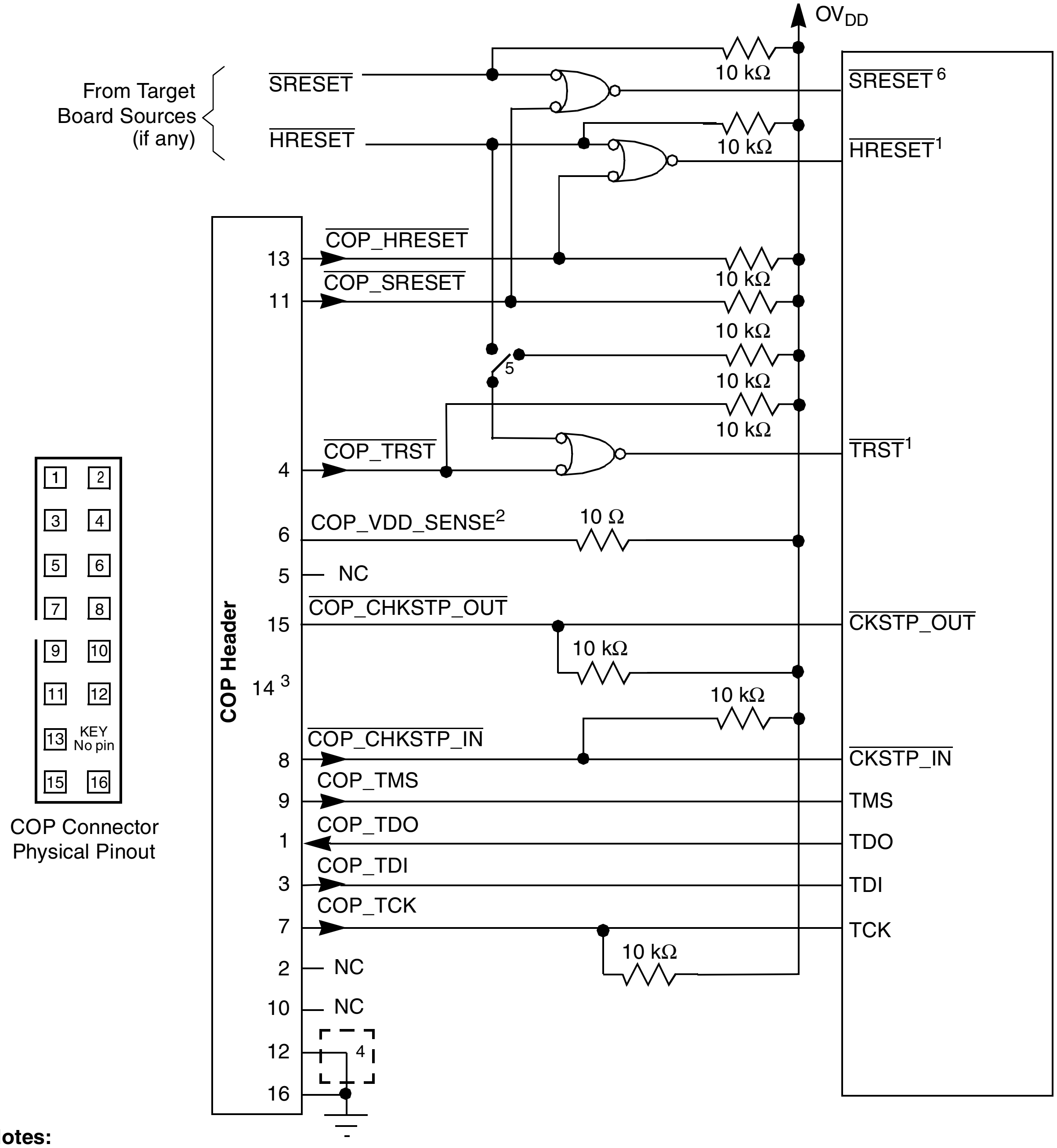
The COP function of these processors allow a remote computer system (typically, a PC with dedicated hardware and debugging software) to access and control the internal operations of the processor. The COP interface connects primarily through the JTAG port of the processor, with some additional status monitoring signals. The COP port requires the ability to independently assert $\overline{\text{HRESET}}$ or $\overline{\text{TRST}}$ in order to fully control the processor. If the target system has independent reset sources, such as voltage monitors, watchdog timers, power supply failures, or push-button switches, then the COP reset signals must be merged into these signals with logic.

The arrangement shown in Figure 60 allows the COP port to independently assert $\overline{\text{HRESET}}$ or $\overline{\text{TRST}}$, while ensuring that the target can drive $\overline{\text{HRESET}}$ as well.

The COP interface has a standard header, shown in Figure 60, for connection to the target system, and is based on the 0.025" square-post, 0.100" centered header assembly (often called a Berg header). The connector typically has pin 14 removed as a connector key.

The COP header adds many benefits such as breakpoints, watchpoints, register and memory examination/modification, and other standard debugger features. An inexpensive option can be to leave the COP header unpopulated until needed.

There is no standardized way to number the COP header; consequently, many different pin numbers have been observed from emulator vendors. Some are numbered top-to-bottom then left-to-right, while others use left-to-right then top-to-bottom, while still others number the pins counter clockwise from pin 1 (as with an IC). Regardless of the numbering, the signal placement recommended in Figure 60 is common to all known emulators.



Notes:

1. The COP port and target board should be able to independently assert $\overline{\text{HRESET}}$ and $\overline{\text{TRST}}$ to the processor in order to fully control the processor as shown here.
2. Populate this with a 10 Ω resistor for short-circuit/current-limiting protection.
3. The KEY location (pin 14) is not physically present on the COP header.
4. Although pin 12 is defined as a No-Connect, some debug tools may use pin 12 as an additional GND pin for improved signal integrity.
5. This switch is included as a precaution for BSDL testing. The switch should be open during BSDL testing to avoid accidentally asserting the $\overline{\text{TRST}}$ line. If BSDL testing is not being performed, this switch should be closed or removed.
6. Asserting $\overline{\text{SRESET}}$ causes a machine check interrupt to the e500 core.

Figure 61. JTAG Interface Connection

Table 62. Document Revision History (continued)

Rev. No.	Substantive Change(s)
1.2	Section 1.1.1—Updated feature list. Section 1.2.1.1—Updated notes for Table 1. Section 1.2.1.2—Removed 5-V PCI interface overshoot and undershoot figure. Section 1.2.1.3—Added this section to summarize impedance driver settings for various interfaces. Section 1.4—Updated rows in Reset Initialization timing specifications table. Added a table with DLL and PLL timing specifications. Section 1.5.2.2—Updated note 6 of DDR SDRAM Output AC Timing Specifications table. Section 1.7—Changed the minimum input low current from -600 to -15 µA for the RGMII DC electrical characteristics. Section 1.7.2—Changed LCS[3:4] to TSEC1_TXD[6:5]. Updated notes regarding LCS[3:4]. Section 1.13.2—Updated the mechanical dimensions diagram for the package. Section 1.13.3—Updated the notes for LBCTL, TRIG_OUT, and ASLEEP. Corrected pin assignments for IIC_SDA and IIC_SCL. Corrected reserved pin assignment of V11 to U11. V11 is actually $\overline{\text{PCI\_STOP}}$. Section 1.14.1—Updated the table for frequency options with respect to platform/CCB frequencies. Section 1.14.4—Edited Frequency options with respect to memory bus speeds.
1.1	Made updates throughout document. Section 1.6.1—Added symbols and note for the GTX_CLK125 timing parameters. Section 1.11.3—Updated pin list table: LGPL5/LSDAMUX to LGPL5, LA[27:29] and LA[30:31] to LA[27:31], TRST to $\overline{\text{TRST}}$, added GBE Clocking section and EC_GTX_CLK125 signal. Figure 50—Updated pin 2 connection information.
1	Original Customer Version.